

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10517214	MAEKAWA ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Jaisle, Cecilia M	1624	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
514	403, 404	10/10/2007	Cecilia Jaisle
548	373.1, 375.1	10/10/2007	Cecilia Jaisle

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>